
PART NUMBER**74AS870NT**

Rochester Electronics**Manufactured Components**

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All re-creations are done with the approval of the Original Component Manufacturer. (OCM)

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-38535
 - Class Q Military
 - Class V Space Level

Qualified Suppliers List of Distributors (QSLD)

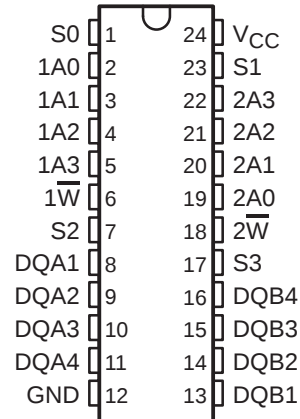
- Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OCM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

- 3-State Buffer-Type Outputs Drive Bus Lines Directly
- Each Register File Has Individual Write-Enable Controls and Address Lines
- Designed Specifically for Multibus Architecture and Overlapping File Operations
- Prioritized B-Input Port Prevents Write Conflicts During Dual-Input Mode
- Package Options Include Plastic Small-Outline (DW) Packages and Standard Plastic (NT) 300-mil DIPs

**DW OR NT PACKAGE
(TOP VIEW)**



description

This device features two 16-word by 4-bit register files. Each register file has individual write-enable ($1\overline{W}$, $2\overline{W}$) controls and address lines. This device has two 4-bit data I/O ports (DQA1–DQA4 and DQB1–DQB4). The data I/O ports can output to bus A and bus B, receive input from bus A and bus B, receive input from bus A and output to bus B, or output to bus A and receive input from bus B. To prevent writing conflicts in the dual-input mode, the B-input port takes priority. Two select (S0 and S1) lines control which port has access to which register. S2 determines whether the A ports are in the input or the output modes and S3 does likewise for the B ports. The address lines (1A0–1A3 or 2A0–2A3) are decoded by an internal 1-of-16 decoder to select which register word is to be accessed. All outputs are 3-state buffer-type outputs designed specifically to drive bus lines directly.

The SN74ALS870 is characterized for operation from 0°C to 70°C.

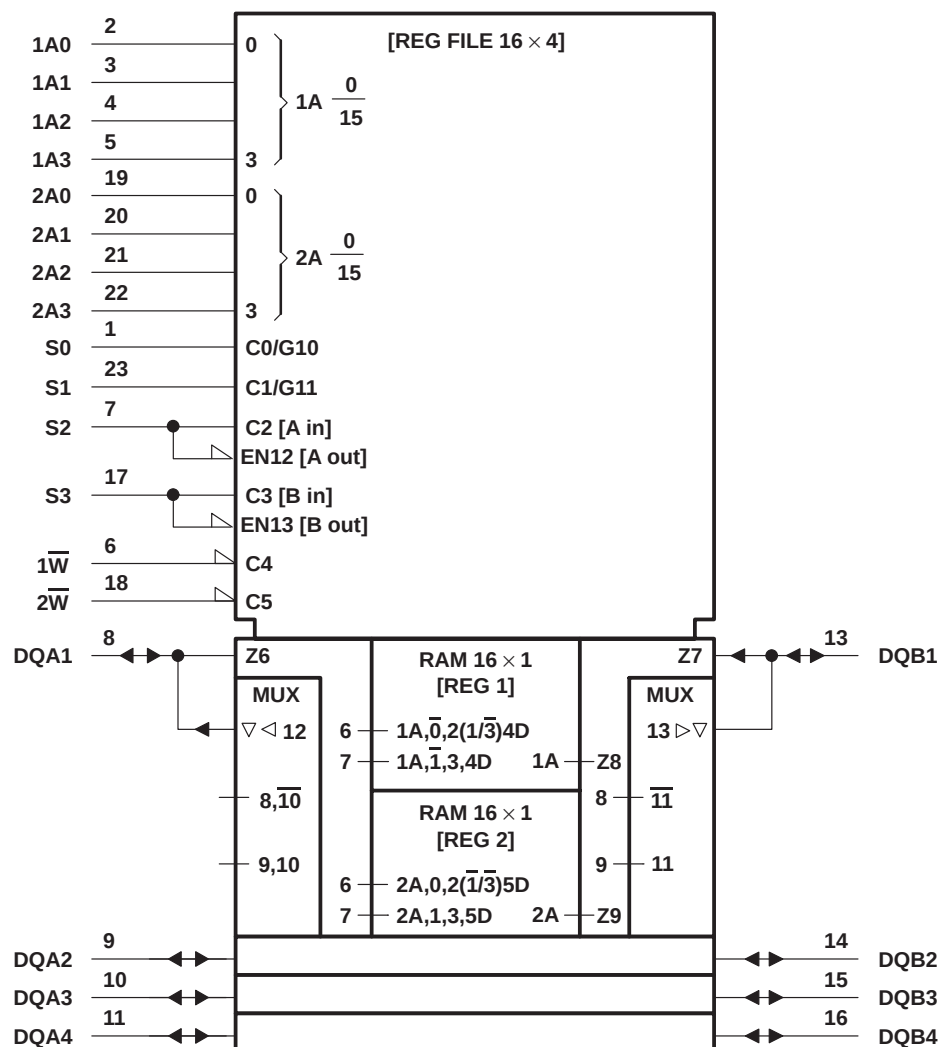
FUNCTION TABLE

FILE SELECT			INPUT/OUTPUT		
S0	S1	FILE SEL	S2	S3	I/O SEL
L	L	1R to A, 1R to B	L	L	A out, B out
H	L	2R to A, 1R to B			
L	H	1R to A, 2R to B			
H	H	2R to A, 2R to B			
L	L	A to 1R, 1R to B	H	L	A in, B out
H	L	A to 2R, 1R to B			
L	H	A to 1R, 2R to B			
H	H	A to 2R, 2R to B			
L	L	1R to A, B to 1R	L	H	A out, B in
H	L	2R to A, B to 1R			
L	H	1R to A, B to 2R			
H	H	2R to A, B to 2R			
L	L	B to 1R	H	H	A in, B in
H	L	A to 2R, B to 1R			
L	H	A to 1R, B to 2R			
H	H	B to 2R			

SN74ALS870 DUAL 16-BY-4 REGISTER FILES

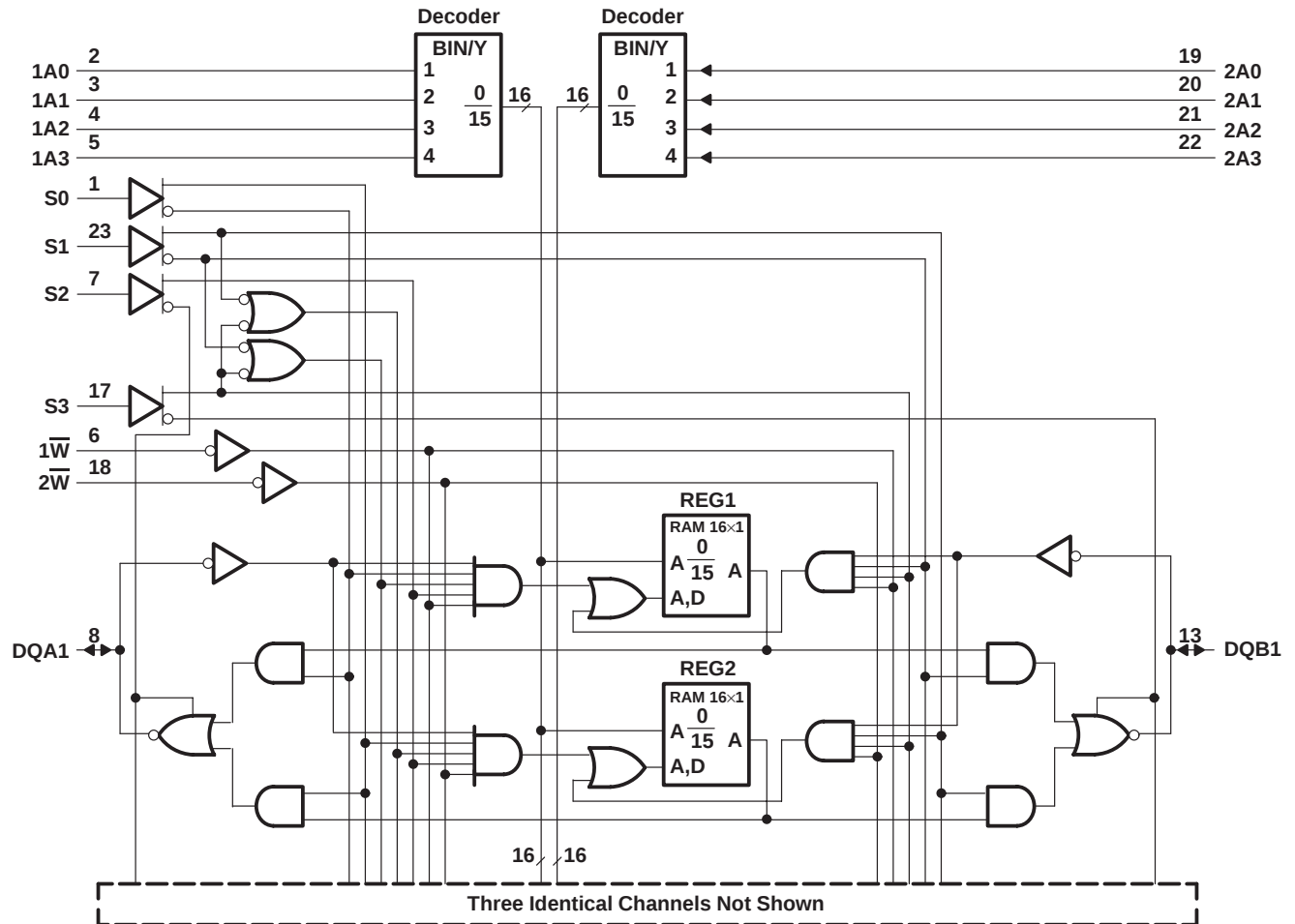
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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V_{CC}	7 V
Input voltage, V_I : All inputs	7 V
I/O ports	5.5 V
Voltage applied to a disabled 3-state output	5.5 V
Operating free-air temperature range, T_A	0°C to 70°C
Storage temperature range	-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

SN74ALS870

DUAL 16-BY-4 REGISTER FILES

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recommended operating conditions

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			V
V_{IL}	Low-level input voltage			0.8	V
I_{OH}	High-level output current			–2.6	mA
I_{OL}	Low-level output current			24	mA
t_w	Pulse duration, write	12			ns
t_{su}	Setup time	Address before write↓	5		ns
		Data before write↑	15		
		Select before write↓	12		
t_h	Hold time	Address before write↓	0		ns
		Data before write↑	0		
		Select before write↓	12		
T_A	Operating free-air temperature	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP†	MAX	UNIT
V_{IK}		$V_{CC} = 4.5\text{ V}$,	$I_I = -18\text{ mA}$			–1.2	V
V_{OH}		$V_{CC} = 4.5\text{ V to } 5.5\text{ V}$,	$I_{OH} = -0.4\text{ mA}$	$V_{CC} - 2$			V
		$V_{CC} = 4.5\text{ V}$,	$I_{OH} = -2.6\text{ mA}$	2.4	3.2		
V_{OL}		$V_{CC} = 4.5\text{ V}$,	$I_{OL} = 24\text{ mA}$	0.35	0.5		V
I_I	Control inputs	$V_{CC} = 5.5\text{ V}$	$V_I = 7\text{ V}$		0.1		mA
	DQA and DQB ports		$V_I = 5.5\text{ V}$		0.2		
I_{IH}	1W and 2W	$V_{CC} = 5.5\text{ V}$,	$V_I = 2.7\text{ V}$		20		μA
	Other control inputs				40		
	DQA and DQB ports‡				50		
I_{IL}	Control inputs	$V_{CC} = 5.5\text{ V}$,	$V_I = 0.4\text{ V}$		–0.2		mA
	DQA and DQB ports‡				–0.2		
$I_{OS}^§$		$V_{CC} = 5.5\text{ V}$,	$V_O = 2.25\text{ V}$	–30		–112	mA
I_{CC}		$V_{CC} = 5.5\text{ V}$			80	110	mA

† All typical values are at $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$.

‡ For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

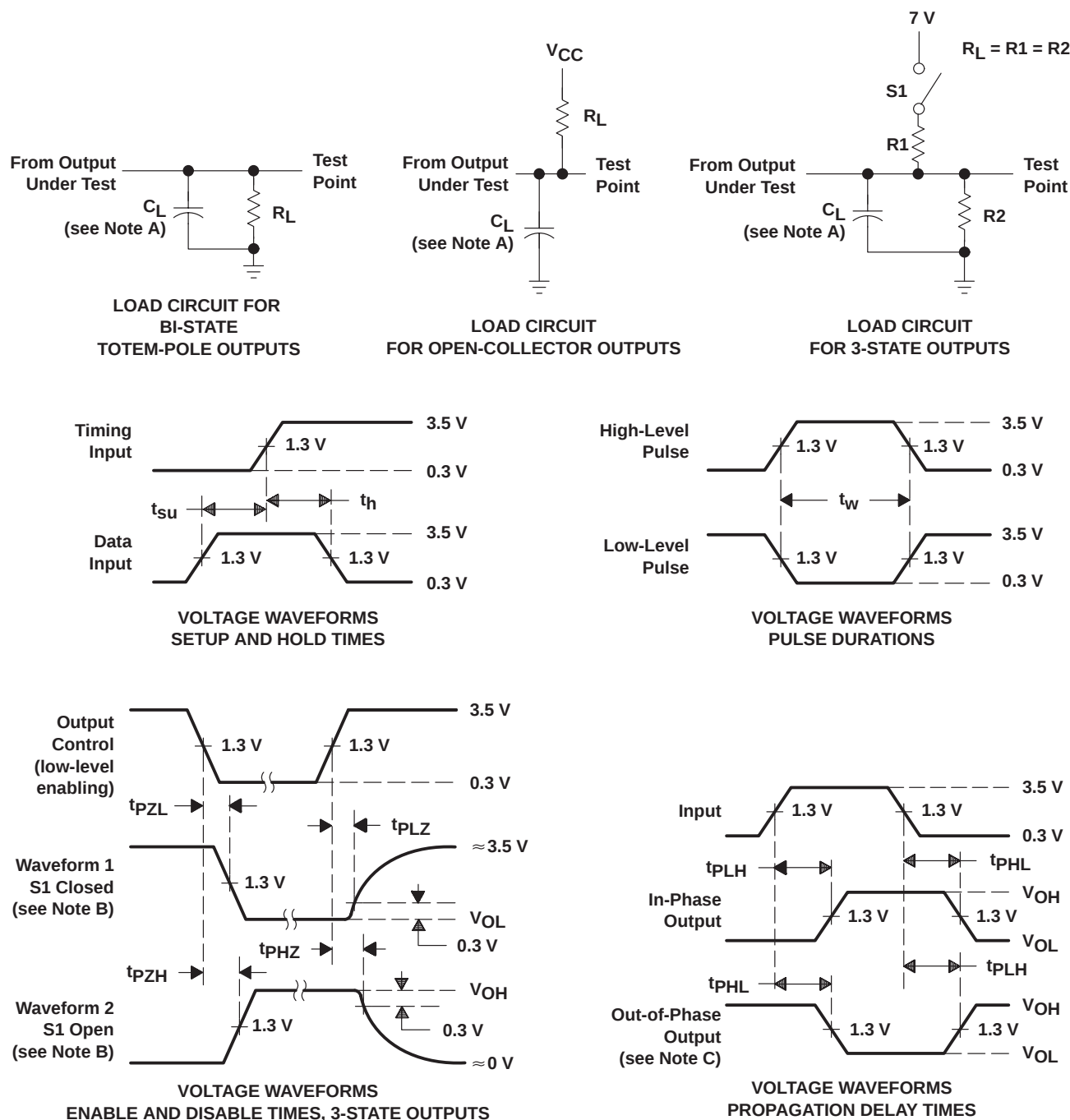
§ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS} .

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 4.5 V to 5.5 V, C _L = 50 pF, R ₁ = 500 Ω, R ₂ = 500 Ω, T _A = MIN to MAX†		UNIT
			MIN	MAX	
t _{a(A)}	Any A	Any DQ	3	19	ns
t _{a(S)}	S0	Any DQA	3	15	ns
	S1	Any DQB	3	15	
t _{dis}	S2	Any DQA	3	14	ns
	S3	Any DQB	3	14	
t _{en}	S2	Any DQA	3	17	ns
	S3	Any DQB	3	17	
t _{pd}	$\overline{W}$	Any DQ	5	23	ns
	DQA	DQB	5	26	
	DQB	DQA	5	26	

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

PARAMETER MEASUREMENT INFORMATION
SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
D. All input pulses have the following characteristics: $PRR \leq 1$ MHz, $t_r = t_f = 2$ ns, duty cycle = 50%.
E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms

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